

<b>Notice of References Cited</b>		Application/Control No. 10/521,674	Applicant(s)/Patent Under Reexamination WEYL ET AL.	
		Examiner BACH T. DINH	Art Unit 1795	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,082,175	07-2000	Yoshikawa et al.	73/23.31
*	B US-2001/0025522	10-2001	Kojima, Takashi	73/31.05
C	US-			
D	US-			
E	US-			
F	US-			
G	US-			
H	US-			
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**FOREIGN PATENT DOCUMENTS**

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N					
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**NON-PATENT DOCUMENTS**

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